

Interference Search

EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	5972	324/158.1.ccls.	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/02/07 10:28
L2	0	1 and (quality near3 test\$2) and (deciding near3 step).clm.	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/02/07 10:34
L3	0	1 and (deciding near3 step) and ((select\$3 or choos\$3) near5 ((non-test\$3 or non\$test\$3 or non adj test\$3) near4 (device or ic or chip or die))).clm.	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/02/07 10:34
L4	0	1 and (deciding near3 step) and ((select\$3 or choos\$3) near5 (device or ic or chip or die)).clm.	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/02/07 10:34
L5	5108	324/765.ccls.	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/02/07 10:34
L6	2	5 and (quality near3 test\$2) and (deciding near3 step).clm.	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/02/07 10:34
L7	1	5 and (deciding near3 step) and ((select\$3 or choos\$3) near5 ((non-test\$3 or non\$test\$3 or non adj test\$3) near4 (device or ic or chip or die))).clm.	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/02/07 10:34

EAST Search History

L8	2	5 and (deciding near3 step) and ((select\$3 or choos\$3) near5 (device or ic or chip or die)).clm.	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/02/07 10:34
L9	2	("4800334" "6246248").PN. OR ("7132844").URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2007/02/07 10:35

EAST Search History

S59	2	("7039543").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/08/15 19:13
S60	2	("6539272").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/08/15 19:35
S61	2	("6751519").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/08/15 19:45
S62	2	("6944567").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/08/15 19:45
S63	20	velez.xa.	US-PGPUB; USPAT; USOCR	OR	ON	2007/01/24 10:33
S64	20	S63	US-PGPUB; USPAT; USOCR	OR	ON	2007/01/24 10:33
S65	102	("4244048" "5726920" "5481205" "6037794" "6127837" "6175936" "5623214" "5852581" "5898629" "5977787" "6151695" "6194739" "6233184" "6233185" "6239603" "4510673" "4612805" "5189363" "5210485" "5366906" "5369358" "5397245" "5461326" "5468157" "5468158" "5489538" "5525912" "5539878" "5571027" "5870408" "5885846" "5898700" "5966025" "5965902" "6058497" "6065142" "6161205" "6181154" "4243937" "4295182" "4296542" "4312117" "4387946" "4410168" "4495628" "4563640" "4568879" "4587480" "4772846" "4799009").pn.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/01/24 10:33

EAST Search History

S66	102	S65	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/01/24 10:36
S67	154	((quality near5 semiconductor) and wafer).ti.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/01/24 10:37
S68	50	((method near4 (quality near5 semiconductor)) and wafer).ti.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/01/24 10:40
S69	0	S68 and "324"/\$.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/01/24 10:38
S70	0	S68 and "702"/\$.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/01/24 10:38
S71	40	(quality near4 ((semiconductor near3 (device\$2 or chip or ic) or dut)) same wafer).ti.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/02/01 09:31
S72	0	S71 and "324"/\$.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/01/24 10:49
S73	0	S71 and "702"/\$.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/01/24 10:50

EAST Search History

S74	343	(quality near4 ((semiconductor near3 (device\$2 or chip or ic) or dut)) same wafer).ab.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/01/24 10:51
S75	335	S74 not S71	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/01/24 10:49
S76	7	S75 and "324"/\$.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/01/24 10:49
S77	0	S75 and "702"/\$.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/01/24 10:50
S78	8	(quality near4 ((semiconductor near3 (device\$2 or chip or ic) or dut)) same wafer).clm.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/02/01 09:32
S79	102	("4244048" "5726920" "5481205" "6037794" "6127837" "6175936" "5623214" "5852581" "5898629" "5977787" "6151695" "6194739" "6233184" "6233185" "6239603" "4510673" "4612805" "5189363" "5210485" "5366906" "5369358" "5397245" "5461326" "5468157" "5468158" "5489538" "5525912" "5539878" "5571027" "5870408" "5885846" "5898700" "5966025" "5965902" "6058497" "6065142" "6161205" "6181154" "4243937" "4295182" "4296542" "4312117" "4387946" "4410168" "4495628" "4563640" "4568879" "4587480" "4772846" "4799009").pn.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/02/01 08:46

EAST Search History

S80	102	S79	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/02/01 08:47
S81	5	("5440720" "5586046" "5621653").PN. OR ("6151695"). URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2007/02/01 08:53
S82	5	("5070297" "6151695" "6380755" "6400173" "6512392").PN. OR ("7071721").URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2007/02/01 08:56
S83	10407	324/765,158.1.ccls.	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/02/01 08:57
S84	51	S83 and (quality near4 data)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/02/01 08:57
S85	7	S84 and algorithm	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/02/01 08:59
S86	44	S84 not S85	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/02/01 09:24
S87	8	(quality near4 ((semiconductor near3 (device\$2 or chip or ic) or dut)) same wafer).clm.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/02/01 09:24

EAST Search History

S88	8	S87	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/02/01 09:26
S89	40	(quality near4 ((semiconductor near3 (device\$2 or chip or ic) or dut)) same wafer).ti.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/02/01 09:26
S90	344	(quality near4 ((semiconductor near3 (device\$2 or chip or ic) or dut)) same wafer).ab:	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/02/01 09:26
S91	336	S90 not S89	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/02/01 09:26
S92	0	S91 and "702"/\$.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/02/01 09:26
S93	0	S92	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/02/01 09:26
S94	50	((method near4 (quality near5 semiconductor)) and wafer).ti.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/02/01 09:26
S95	50	S94	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/02/01 09:29

EAST Search History

S96	7	S91 and "324"/\$.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/02/01 09:29
S97	7	S96	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/02/01 09:30
S98	40	S89	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/02/01 09:30
S99	40	(quality near4 ((semiconductor near3 (device\$2 or chip or ic) or dut)) same wafer).ti.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/02/01 09:31
S10 0	8	(quality near4 ((semiconductor near3 (device\$2 or chip or ic) or dut)) same wafer).clm.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/02/01 15:42
S10 1	1278	702/117-118.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/02/01 15:42
S10 2	159	S101 and additional near3 test	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/02/01 15:50
S10 3	303	S101 and addition\$3 near3 test\$3	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/02/01 15:50

EAST Search History

S10 4	303	S101 and (addition\$3 near3 test\$3)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/02/01 15:50
S10 5	83	S104 and wafer	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/02/01 15:50
S10 6	10398	324/765,158.1.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/02/01 15:49
S10 7	452	S106 and additional near3 test	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/02/01 15:50
S10 8	1256	S106 and addition\$3 near3 test\$3	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/02/01 15:50
S10 9	1256	S106 and (addition\$3 near3 test\$3)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/02/01 15:50
S11 0	583	S109 and wafer	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/02/01 15:50
S11 1	10398	324/158.1,765.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/02/02 09:38

EAST Search History

S11 2	2086	S111 and (wafer same ((integrated near3 circuit\$3) or ic or dut or chip or die))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/02/02 11:11
S11 3	371	S112 and prober	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/02/02 09:52
S11 4	225	S113 and (pass or fail\$4)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/02/02 09:52
S11 5	125	S114 and (memory or cpu or computer)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/02/02 09:53
S11 6	98	S115 and 324/765.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/02/02 09:53
S11 7	19	("3615466" "3751647" "4144493" "5047947" "5351202" "5394348" "5396433" "5539652" "5598341" "T959005").PN. OR ("5793650").URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2007/02/02 10:11
S11 8	2	("6759863").PN.	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/02/02 10:11

EAST Search History

S11 9	64	("3689885" "4002974" "4105950" "4517532" "4985681" "5030908" "5039602" "5059899" "5068521" "5095267" "5113184" "5149662" "5192913" "5204559" "5252914" "5266890" "5279975" "5315241" "5365204" "5446395" "5457400" "5619463" "5625288" "5714888" "5790479" "5811983" "5818250" "5867033" "5892368" "5905383" "5923676" "5952840" "5983363" "5994915" "5995428" "5999009" "6005407" "6005829" "6058497" "6075417" "6087842" "6097203" "6119255" "6133582" "6134191" "6161205" "6166607" "6169694" "6184696" "6189120" "6219305" "6223314" "6236223" "6239591" "6239603" "6356514" "6466520" "6512392" "6538936" "6544807").PN. OR ("6759863").URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2007/02/02 10:13
S12 0	64	("4075632" "4360810" "4782345" "4786907" "4816389" "4835377" "4853705" "4864158" "4888591" "4999636" "5028866" "5030807" "5055659" "5336988" "5479160" "5485520" "5504485" "5510795" "5521601" "5528222" "5538803" "5550547" "5552778" "5554974" "5563583" "5565847" "5606323" "5635693" "5673037" "5680106" "5682143" "5729201" "5729697" "5736929" "5737710" "5739754" "5767789" "5771021" "5777561" "5786626" "5812065" "5821859" "5825329" "5826328" "5828318" "5828693" "5831532" "5850181" "5850187" "5874902" "6049308").PN. OR ("6236223"). URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2007/02/02 10:16
S12 1	3750	324/765.ccls.	US-PGPUB; USPAT; USOCR	OR	ON	2007/02/02 10:16

EAST Search History

S12 2	5099	324/765.ccls.	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/02/02 10:16
S12 3	132	S122 and select\$4 near8 (((integrated near3 circuit) or ic or chip or die) near5 wafer)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/02/02 11:12
S12 4	14	S123 and judg\$4	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/02/02 10:19
S12 5	118	S123 not S124	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/02/02 10:36
S12 6	5	("5623214" "5758537" "5818249" "6210983" "6764866").PN. OR ("6943573").URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2007/02/02 10:51
S12 7	10	("4875002" "4985676" "5286656").PN. OR ("5654632"). URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2007/02/02 10:56
S12 8	26	("3751647" "3784907" "3790767" "4074851" "4176780" "4191996" "4335457" "4430735" "4451970" "4510603" "4703436" "4710932" "4728883").PN. OR ("4875002"). URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2007/02/02 10:57
S12 9	15	("20020084798" "4875002" "5384531" "5583875" "5734274" "5793945" "5923602" "5973541" "6112940" "6128757" "6134685" "6360333" "6430705" "6472899" "6625758").PN. OR ("7112979"). URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2007/02/02 10:57

EAST Search History

S13 0	13	("5337262" "5644251" "5668745" "5670890").PN. OR ("6128757"). URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2007/02/02 11:05
S13 1	1278	702/117-118.ccls.	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/02/02 11:11
S13 2	206	S131 and (wafer same ((integrated near3 circuit\$3) or ic or dut or chip or die))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/02/02 11:11
S13 3	0	S131 and ((select\$4 near8 (((integrated near3 circuit) or ic or chip or die) near5 wafer)) same decid\$4)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/02/02 11:12
S13 4	22	S131 and (select\$4 near8 (((integrated near3 circuit) or ic or chip or die) near5 wafer))	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/02/02 11:20
S13 5	2058	(select\$4 near8 (((integrated near3 circuit) or ic or chip or die) near5 wafer))	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/02/02 11:35
S13 6	129	S135 and (prob\$3 near5 measur\$4)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/02/02 11:22
S13 7	0	S136 and ((decid\$4 or determin\$3) near3 re\$test\$3)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/02/02 11:23

EAST Search History

S13 8	44	S136 and ((decid\$4 or determin\$3) near3 test\$3)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/02/02 11:29
S13 9	1	324/765.ccls. and (deciding near3 means)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/02/02 11:31
S14 0	21	324/765.ccls. and (deciding near3 whether)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/02/02 11:35
S14 1	6	(select\$4 near8 (((integrated near3 circuit) or ic or chip or die) near5 wafer)) and (deciding near3 whether)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/02/02 13:21
S14 2	8	probe near5 select\$3 near4 ((ic near4 wafer))	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/02/02 13:24
S14 3	21	probe near5 select\$3 same ((ic near4 wafer))	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/02/02 13:25
S14 4	13	S143 not S142	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/02/02 13:24

EAST Search History

S14 5	187	probe near5 select\$3 same (((ic or (integrated near3 circuit\$3) or chip or die) near4 wafer))	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/02/02 14:15
S14 6	3	S145 and (decid\$3 near5 whether)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/02/02 13:26
S14 7	7	("3849872" "5053700" "5059899" "5442282" "5446395" "5557573" "5808947").PN. OR ("6930499").URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2007/02/02 14:13
S14 8	7	S145 and (based near4 (test near3 result\$2))	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/02/02 14:34
S14 9	130	324/765.ccls. and (based near4 (test near3 result\$2))	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/02/02 14:35
S15 0	84	S149 and wafer	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/02/02 17:00
S15 1	2	("6144210").PN.	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/02/02 17:14

EAST Search History

S15 2	667	324/765.ccls. and pass and fail	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/02/02 17:35
S15 3	304	S152 and ((ic or (integrat\$3 near3 circuit\$3) or die or chip) near8 wafer)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/02/02 17:18
S15 4	21	S153 and select\$3 and decid\$3	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/02/02 17:19
S15 5	2	("20020053921").PN.	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/02/02 17:19
S15 6	7	("5332973" "5392293" "5519333" "5889408" "5914615" "6175244" "6342790").PN. OR ("6889164").URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2007/02/02 17:29
S15 7	2	("6166557").PN.	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/02/02 17:30
S15 8	0	("testsamedecid\$3sameselect\$3"). PN.	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/02/02 17:31

EAST Search History

S15 9	3120	test same decid\$3 same select\$3	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/02/02 17:31
S16 0	135	S159 and "324"/\$.ccls.	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/02/02 17:32
S16 1	24	S160 and wafer	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/02/02 17:32
S16 2	0	324/765.ccls. and ((pass and fail) same stop and (nonstop or no\$stop))	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/02/02 17:36
S16 3	55	((pass and fail) same stop and (nonstop or no\$stop))	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/02/02 17:37
S16 4	0	S163 and wafer	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/02/02 17:37
S16 5	22	test\$3 and ((pass and fail) same stop and (nonstop or no\$stop))	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/02/02 18:00
S16 6	0	("8114652").PN.	JPO	OR	OFF	2007/02/02 18:00

EAST Search History

S16 7	0	("8114652").PN.	JPO	OR	OFF	2007/02/02 18:00
S16 8	0	("8114652").PN.	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/02/02 18:01
S16 9	0	"8114652"	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/02/02 18:01
S17 0	2	"08114652"	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/02/02 18:01